


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/711,981	CHEN ET AL.	
	Examiner	Art Unit	
	Oanh Duong	2155	

SEARCHED			
Class	Subclass	Date	Examiner
709	223-226, 229	7/24/2006	O.D
370	395.21	7/24/2006	O.D
370	395.41	7/24/2006	O.D

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
update EAST text search of USPAT, JPO, EPO, DERWENT, IBM_TDB, US-PGPUB	7/24/2006	O.D